

FIG. 2A

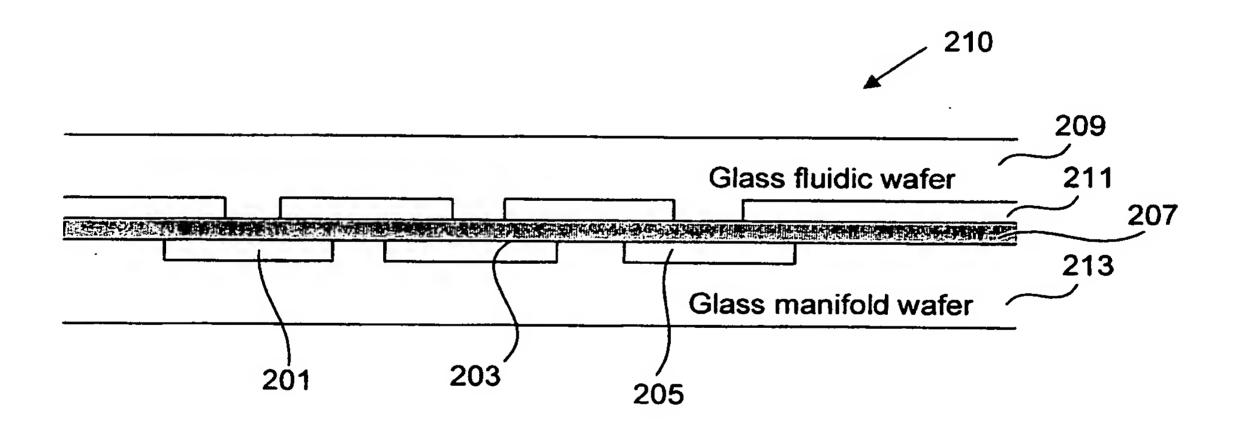


FIG. 2B

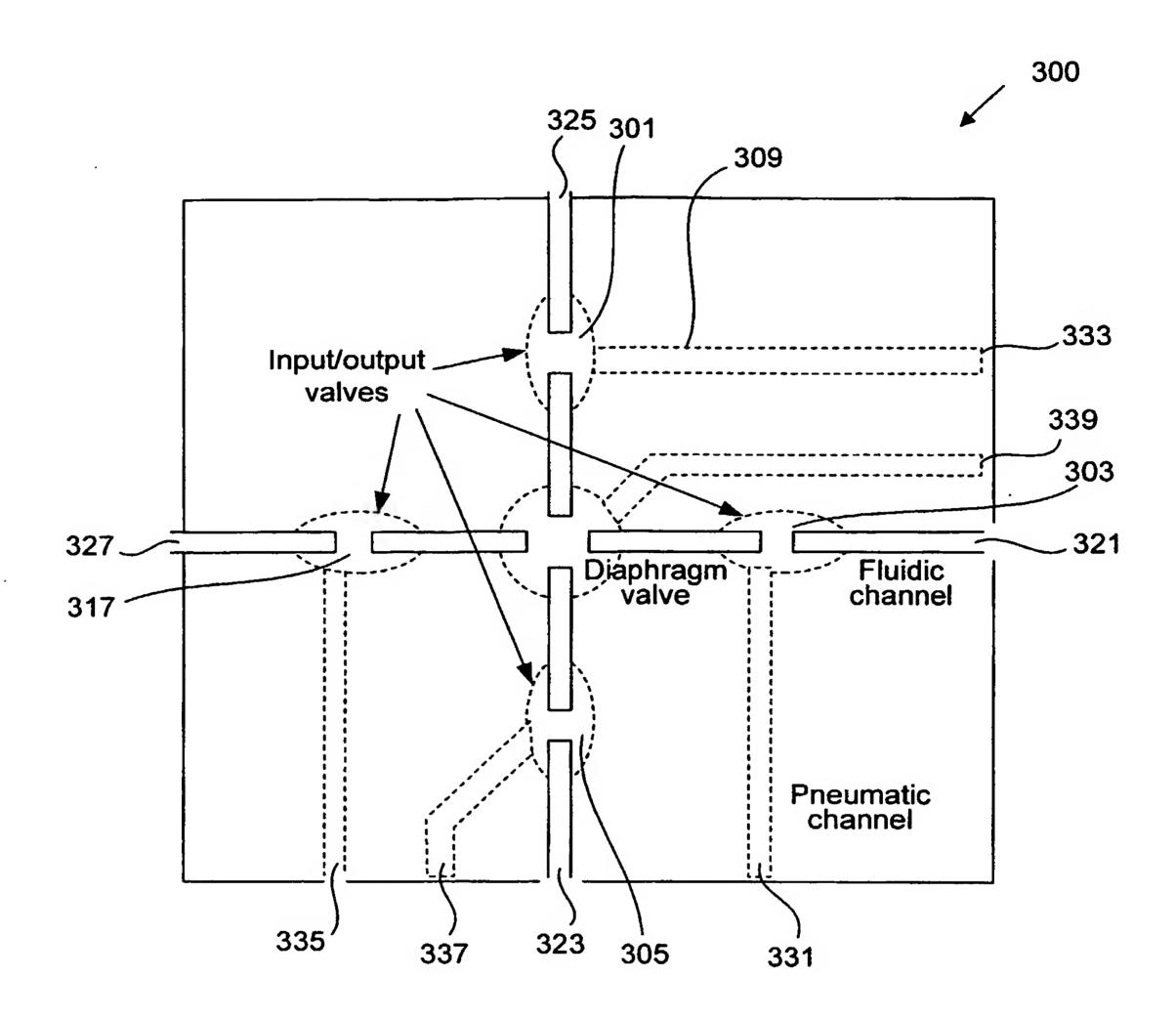


FIG. 3

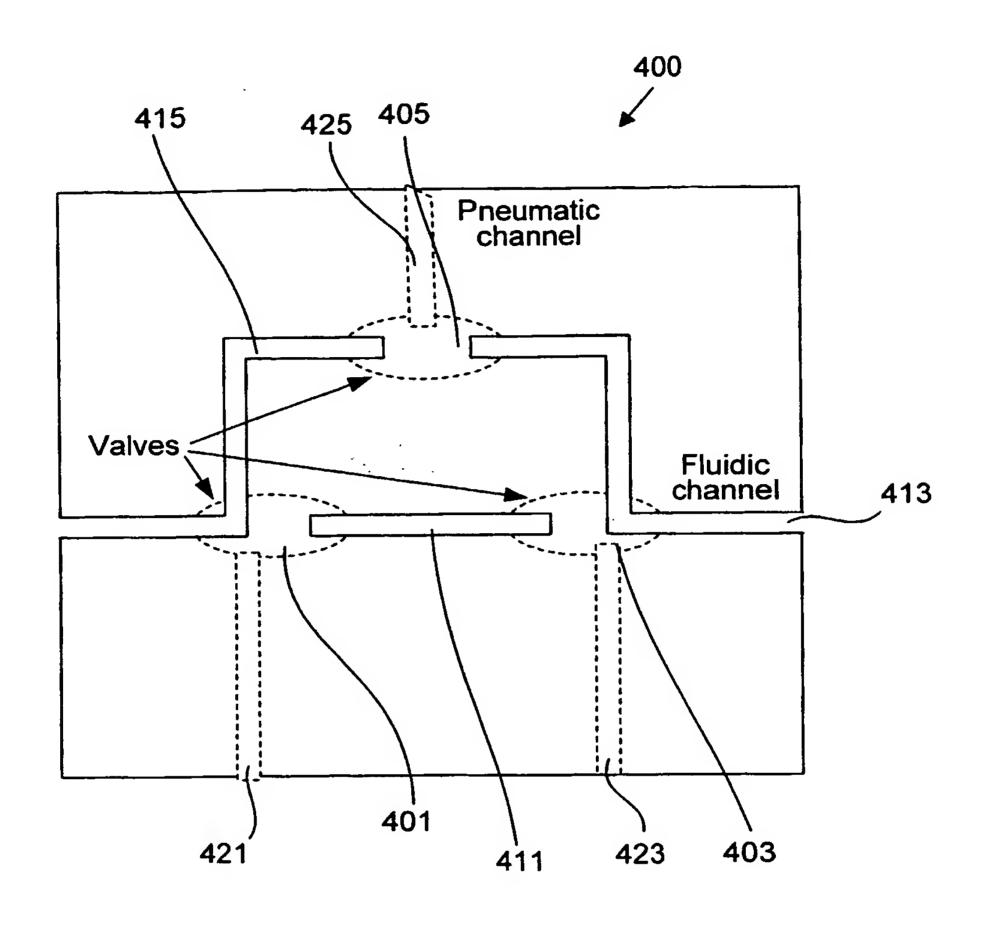


FIG. 4

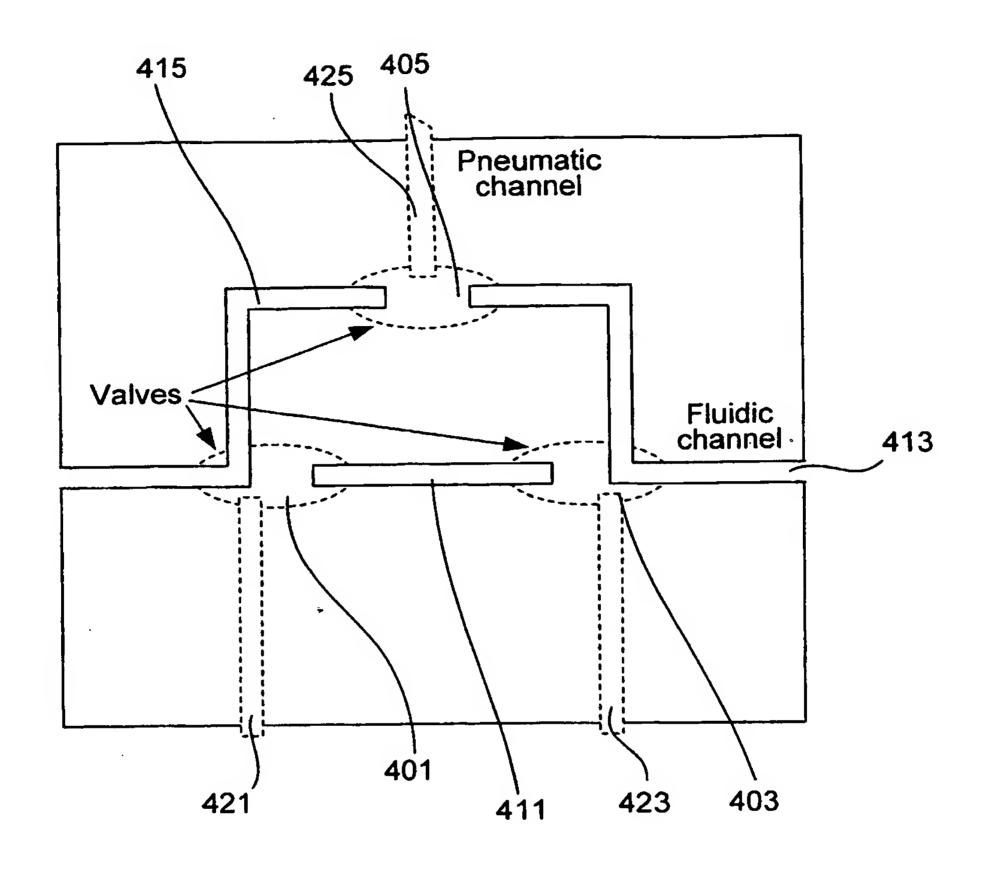
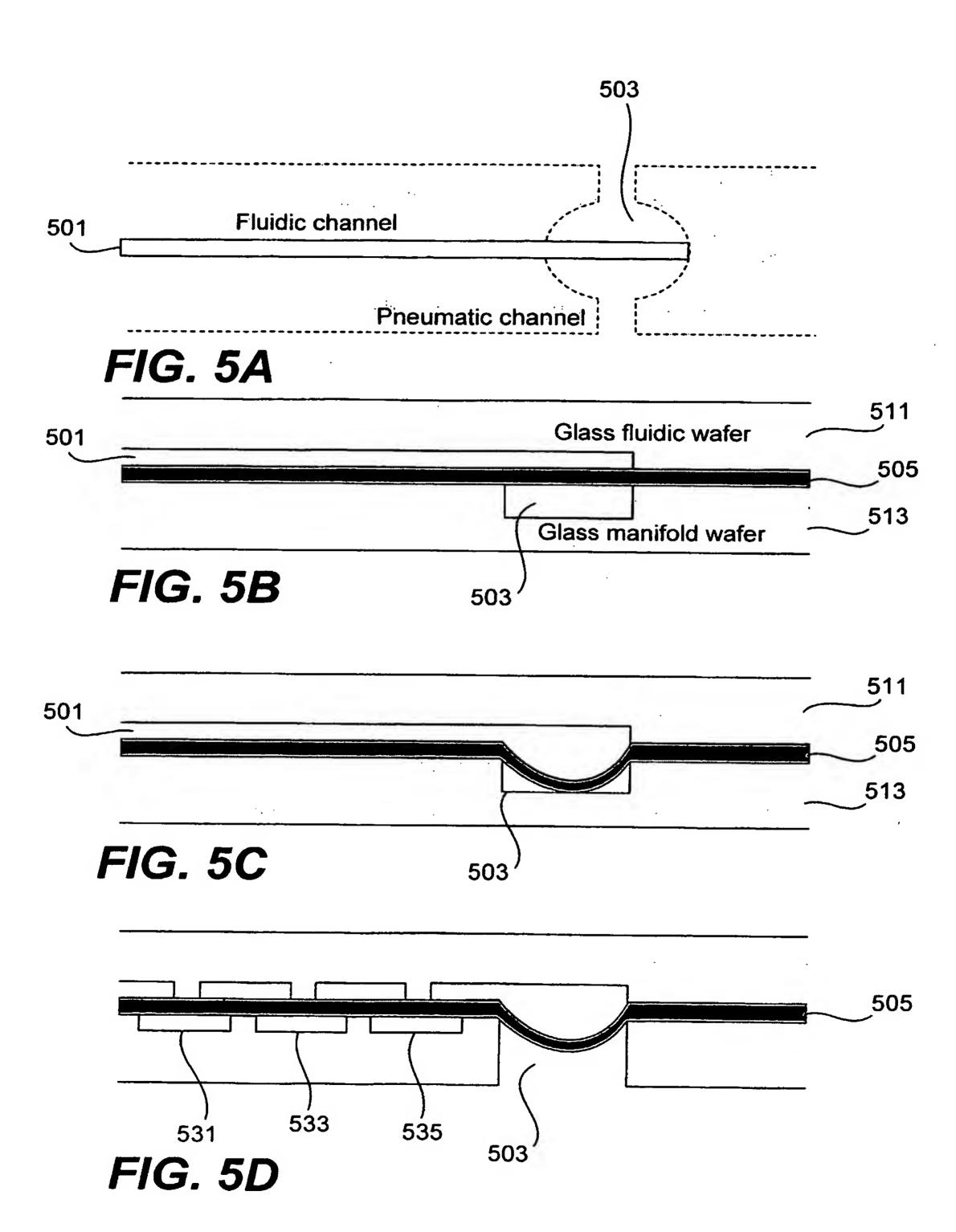
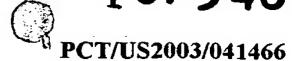


FIG. 4





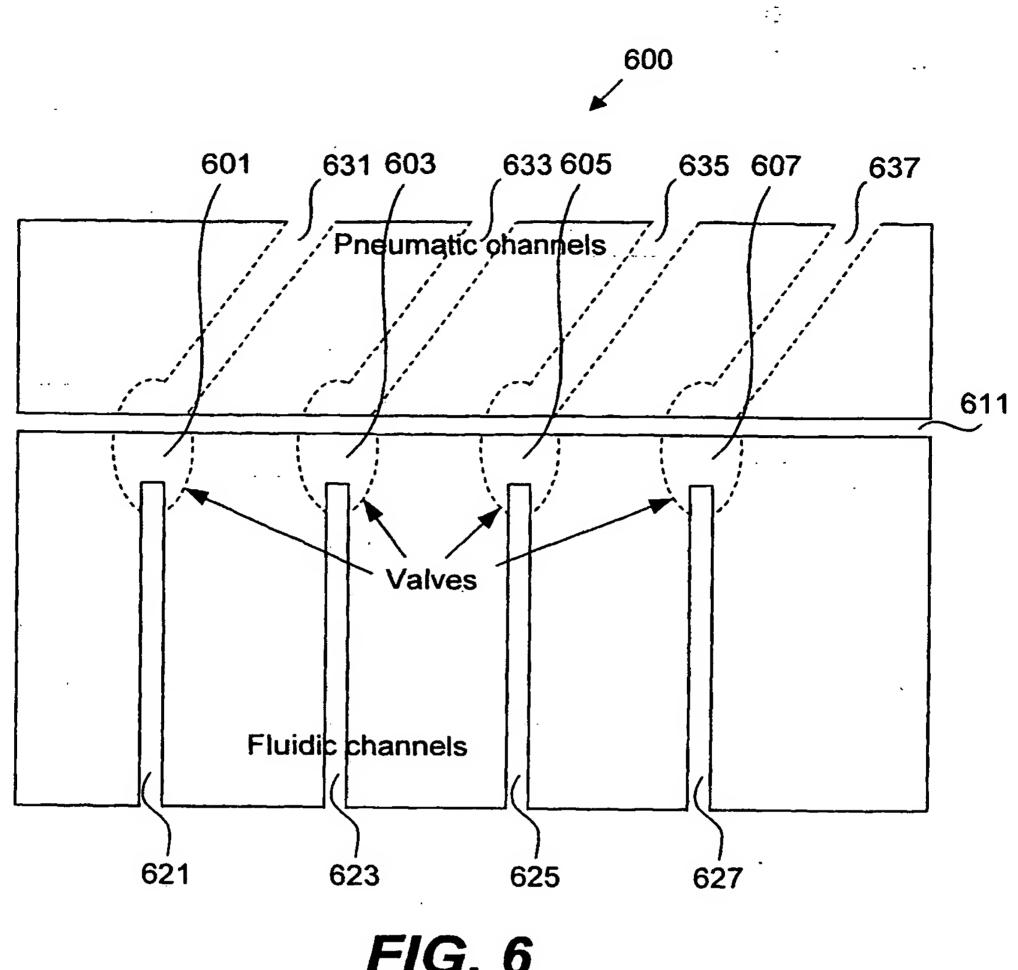


FIG. 6

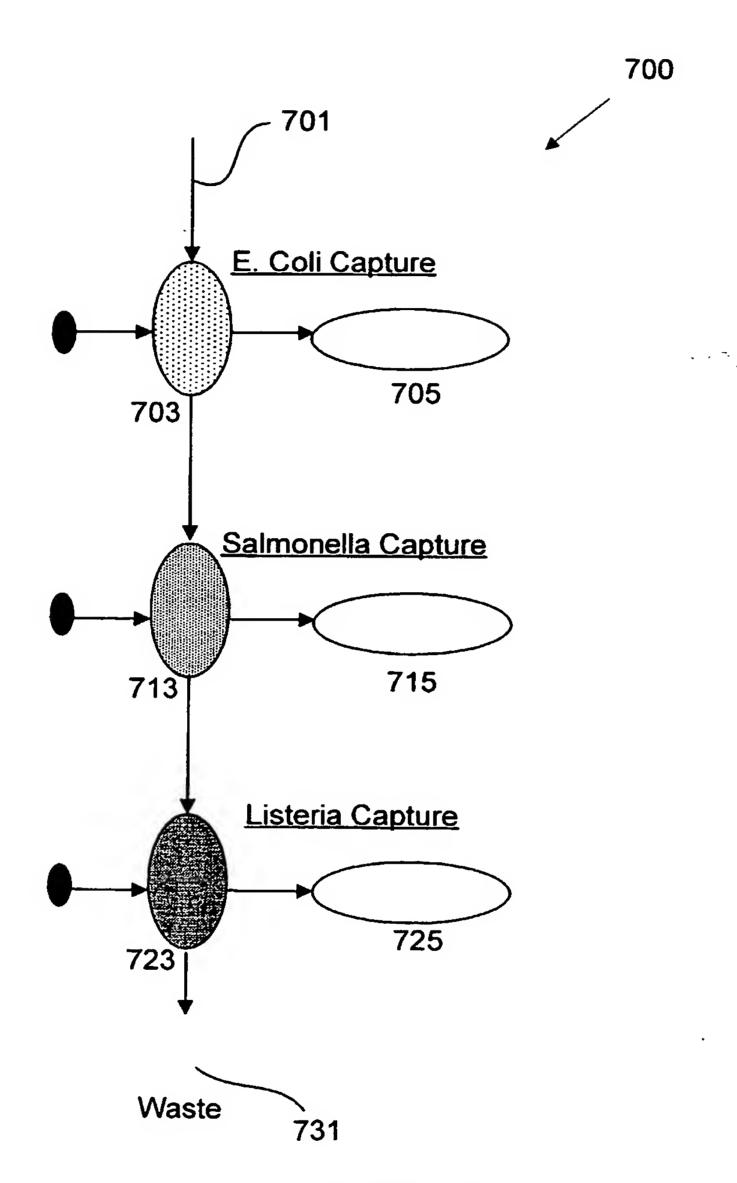


FIG. 7

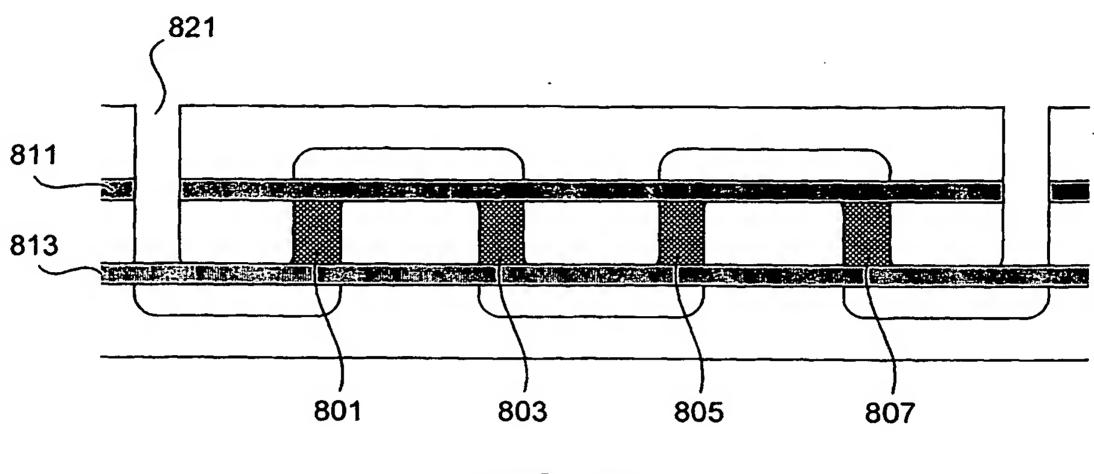


FIG. 8

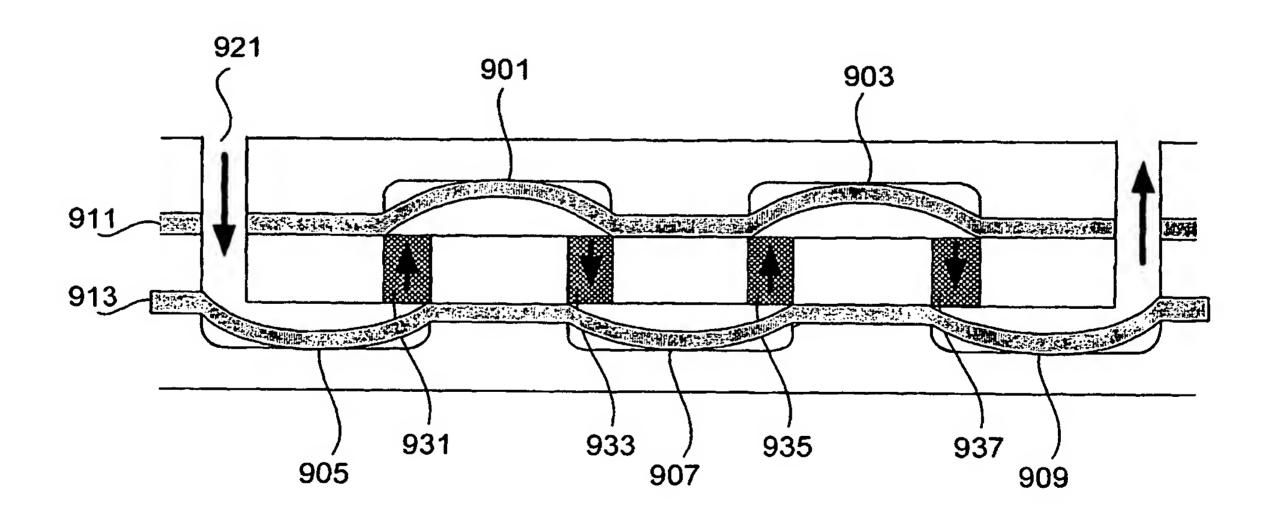
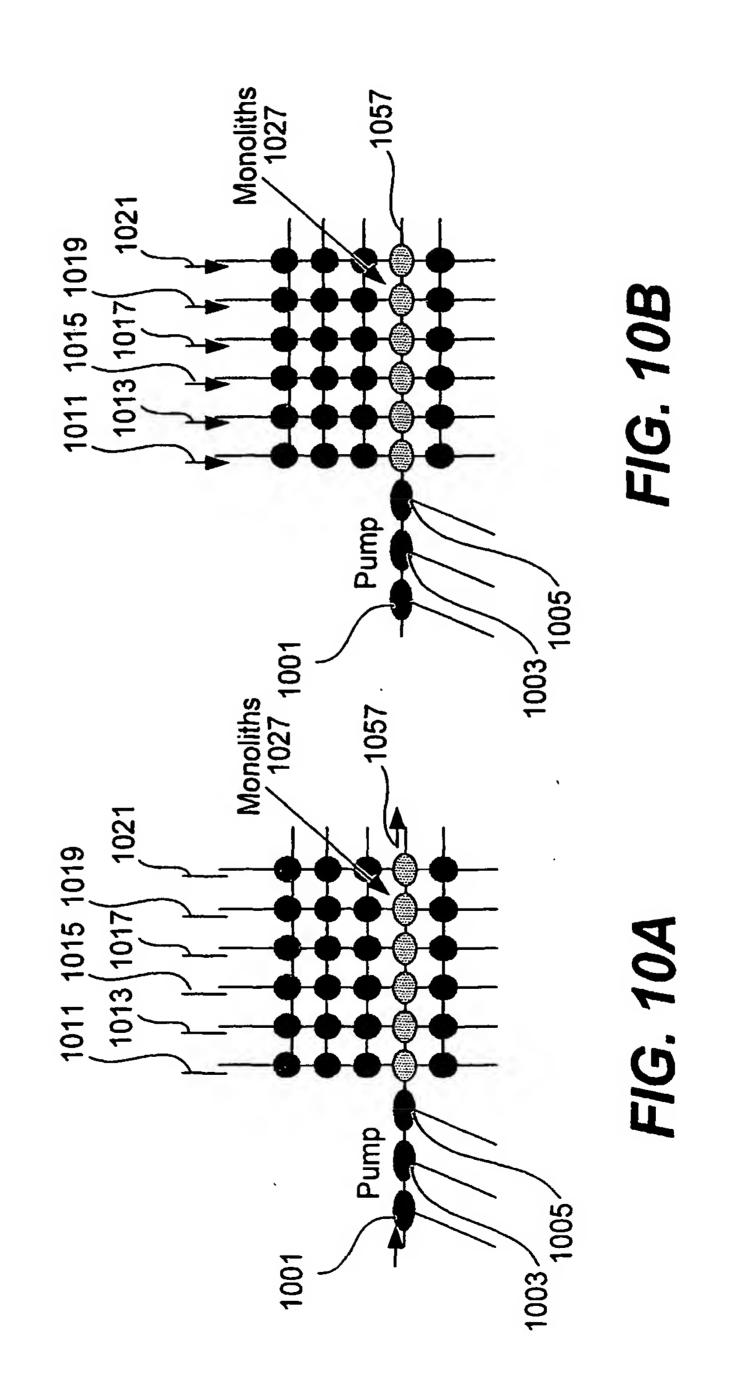
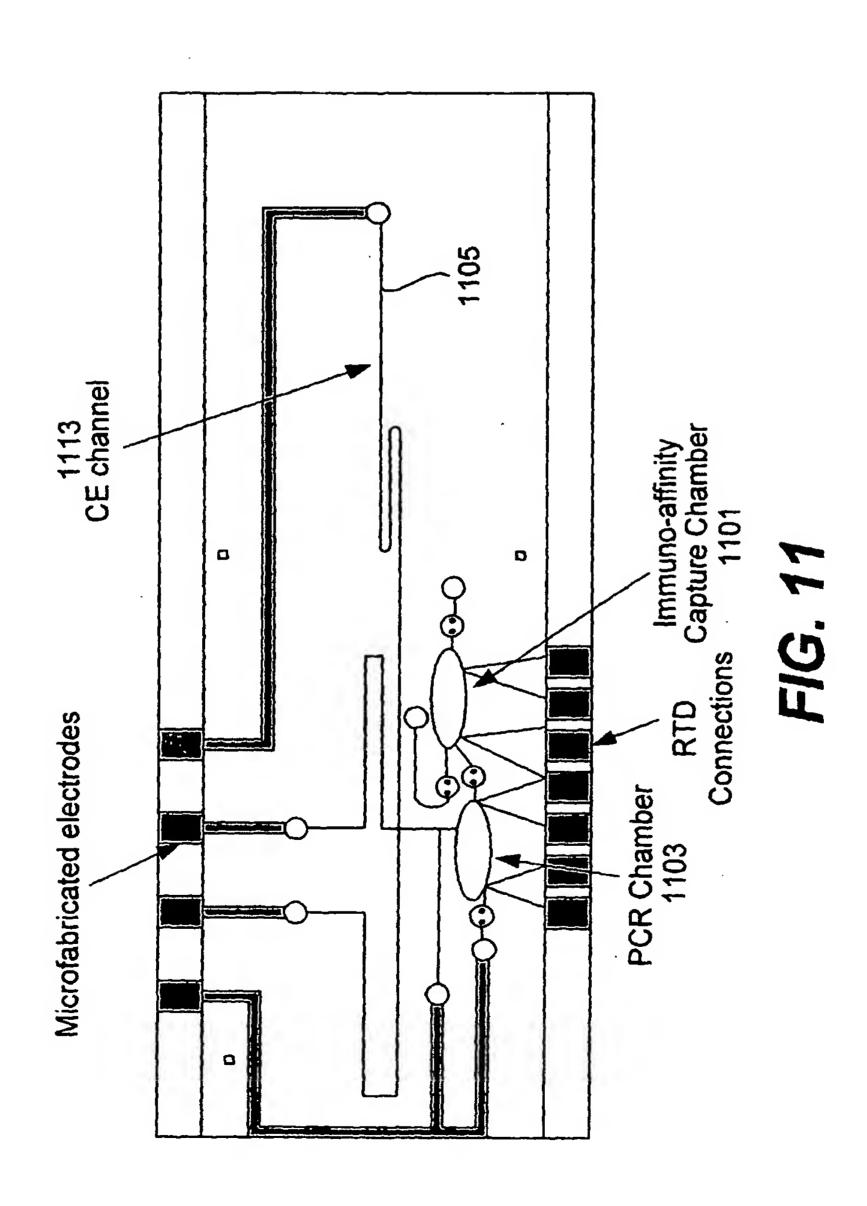


FIG. 9





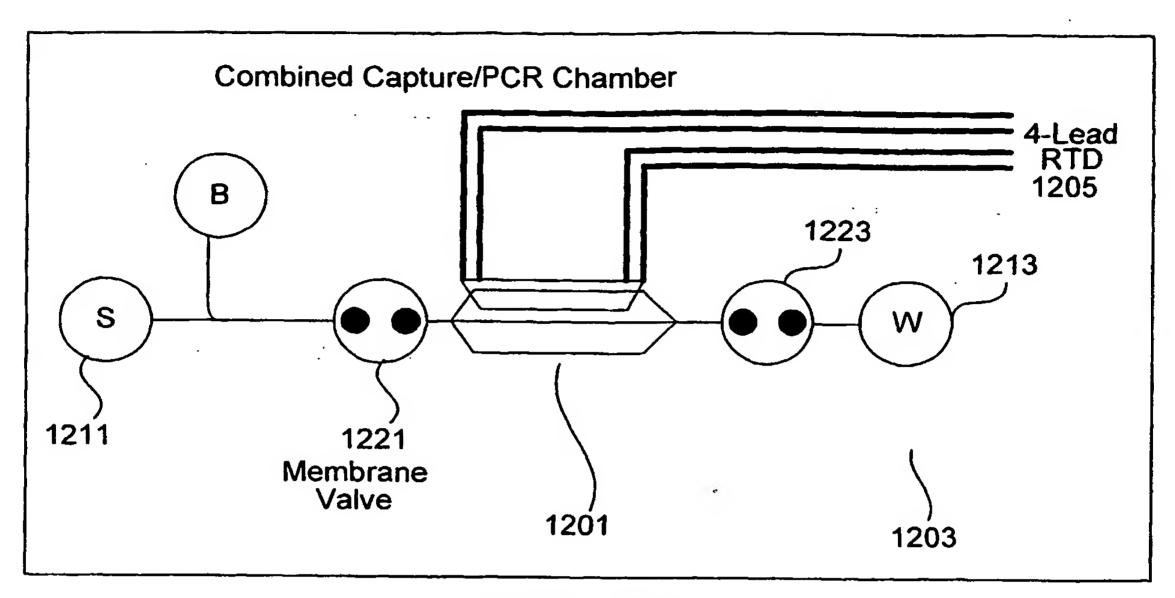


FIG. 12

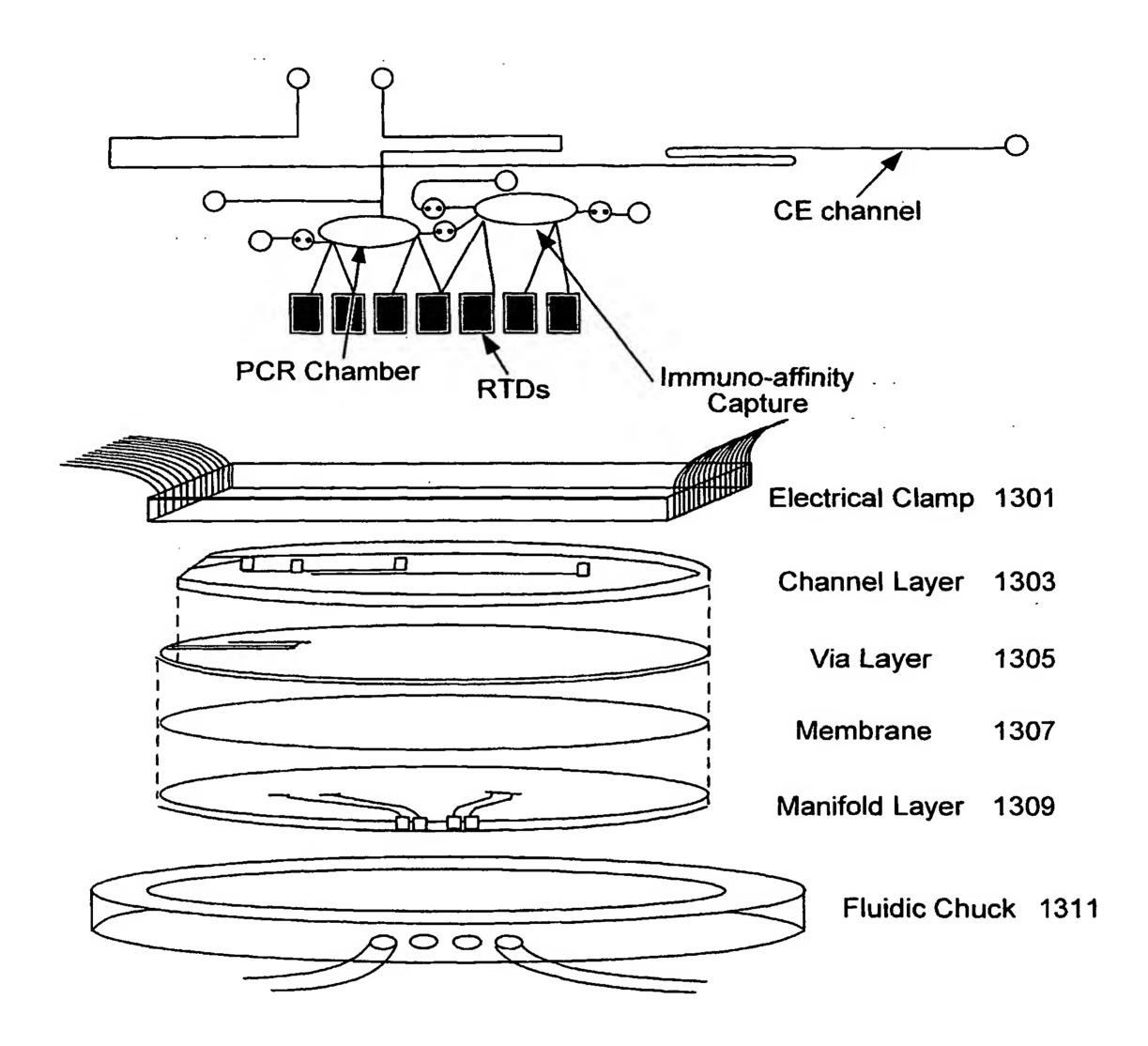


FIG. 13A

PCT/US2003/041466

1381 1383 A) B) 10 nm Ti / 200 nm Pt D263 D263 10 nm Ti / 200 nm Pt Legend \square = SiO₂, glass 🔳 = Au 圖 = Ti/Pt 图 = A-Si ■ photoresist

FIG. 13B

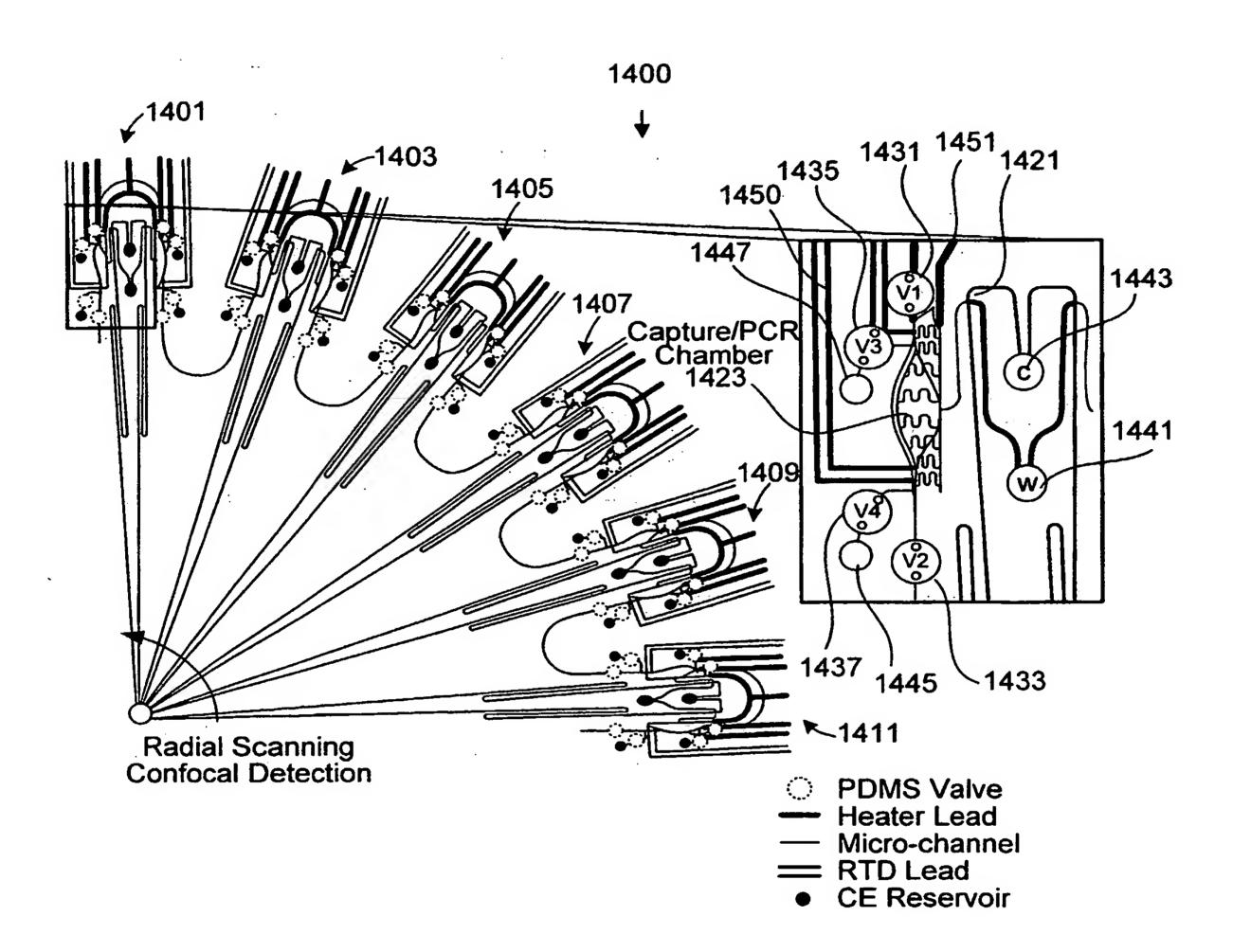


FIG. 14

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